Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/653,222	LI, JIN	
Examiner	Art Unit	
Linsenh Nauven	2815	

	SEAR	CHED	
Class	Subclass	Date	Examiner
257	294, 440	6/6/2006	Jζ
257	431, 432	6/6/2006	JN
257	233, 234	6/6/2006	JN
257	e33.067	6/6/2006	JN

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	<u></u>		

SEARCH   (INCLUDING SEAR		)
	DATE	EXMR
Search history in EAST	6/6/2006	JN